# NALOG Product/Process Change Notice - PCN 16\_0268 Rev. -

Analog Devices, Inc. Three Technology Way Norwood, Massachusetts 02062-9106

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date. ADI contact information is listed below.

PCN Title:	ADuM3400/ADuM3401/ADuM3402 Die Revision, Data Sheet Change and High Voltage Test Platform Migration			
Publication Date:	15-Feb-2017			
Effectivity Date:	16-May-2017 (the earliest date that a customer could expect to receive changed material)			

#### **Revision Description:**

Initial Release

### Description Of Change

Die:

Increased pulse width of disable signal for refresh block. Increased separation between refresh high pulses and falling edge pulses. Increased minimum separation between refresh low edge pulses and rising edge pulses by increasing edge look ahead time.

Data Sheet:

Increased minimum operating voltage from 2.7V to 3.0V.

#### Test Platform:

The high voltage test platform used to verify the insulation performance of the ADuM3400/ADuM3401/ADUM3402 products during production will be migrated from the Harris-Tuvey 9464 to the Mess-& Prüfsysteme GmbH (MPS) PD test system.

# Reason For Change

#### Die and Data Sheet:

To ensure continuity of supply through improved manufacturability.

Test Platform:

To maintain future continuity of supply and gain the ability to datalog high voltage production test measurements. ADI is currently relying on an aging high voltage test platform (Harris-Tuvey 9464) for the ADuM340x products.

# Impact of the change (positive or negative) on fit, form, function & reliability

No change to fit, form, or reliability. Devices will not be recommended for use with power supply voltages below 3.0V.

# Summary of Supporting Information

Qualification has been performed per Industry Standard Test Methods. See attached Qualification Results Summary. Test correlation and validation has been performed, see attached test correlation report. Changes will be reflected in Rev E of the data sheet.

#### Supporting Documents

Attachment 1: Type: Qualification Results Summary ADI\_PCN\_16\_0268\_Rev\_\_ADuM340x\_Qual\_Results\_Summary.pdf

# Attachment 2: Type: Test Correlation Report ADI\_PCN\_16\_0268\_Rev\_\_\_ADuM340x\_HT\_\_MPS\_Test\_Correlation\_Report.pdf

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.					
Americas:	PCN_Americas@analog.com	Europe:	PCN_Europe@analog.com	Japan:	PCN_Japan@analog.com
				Rest of Asia:	PCN_ROA@analog.com

Appendix A - Affected ADI Models						
Added Parts On This Revision - Product Family / Model Number (18)						
ADUM3400/ADUM3400ARWZ	ADUM3400 / ADUM3400ARWZ-RL	ADUM3400 / ADUM3400BRWZ	ADUM3400/ADUM3400BRWZ-RL	ADUM3400 / ADUM3400CRWZ		
ADUM3400/ADUM3400CRWZ-RL	ADUM3401 / ADUM3401ARWZ	ADUM3401 / ADUM3401ARWZ-RL	ADUM3401 / ADUM3401BRWZ	ADUM3401 / ADUM3401BRWZ-RL		
ADUM3401 / ADUM3401CRWZ	ADUM3401 / ADUM3401CRWZ-RL	ADUM3402/ADUM3402ARWZ	ADUM3402/ADUM3402ARWZ-RL	ADUM3402 / ADUM3402BRWZ		
ADUM3402 / ADUM3402BRWZ-RL	ADUM3402/ADUM3402CRWZ	ADUM3402/ADUM3402CRWZ-RL				

Appendix B - Revision History					
Rev	Publish Date	Effectivity Date	Rev Description		
Rev	15-Feb-2017	16-May-2017	Initial Release		

Analog Devices, Inc.

Docld:3940 Parent Docld:None Layout Rev:7